

Substitute for Form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>					Complete if Known	
					Application Number	
					Filing Date	
					First Named Inventor:	
					Art Unit	
					Stephen W. Smith	
					2829	
					Kobert	
					Attorney Docket Number	
					53470P020D	
U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)				
RL	—	US-	3,609,991	10/5/1971	Chu et al.	—
RL	—	US-	3,714,572	1/30/1973	Ham et al.	—
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RL	—	US-	4,698,728	10/6/1987	Tustaniwskyj et al.	—
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RL	—	US-	4,791,983	12/20/1988	Nicol et al.	—
RL	—	US-	4,809,134	2/25/1989	Tustaniwskyj et al.	—
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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)				

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Sheet	2	of	5	Attorney Docket Number		53470P020D

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RL	—	US-	4,865,123	9/12/1989	Kawashima et al.	—
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
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RK	-	Rohit Kapur, Jaehong Park, and M. Ray Mercer, "All Tests For A Fault Not Equally Valuable For Defect Detection," IEEE, 1991 International Test Conference, pp. 762-769 (1991) <i>(No Month)</i>	/
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RK	-	Robert C. Aitken, "A Comparison of Defect Models for Fault Location with Idcq Measurements," IEEE, 1992 International Test Conference, pp. 778-787 (1992) <i>(No Month)</i>	/
RK	-	Yukiya Muira and Kozo Kinoshita, "Circuit Design for Built-in Current Testing," IEEE, 1992 International Test Conference, pp. 873-881 (1992) <i>(No Month)</i>	/
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RK	-	Kenneth M. Wallquist, Alan W. Righter, and Charles F. Hawkins, "A General Purpose IDDQ Measurement Circuit," IEEE, 1993 International Test Conference, pp. 642-651 (1993) <i>(No Month)</i>	/

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Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T ²
RK	—	Jerry M. Soden, Ronald R. Fritzmeier, and Charles F. Hawkins, "Zero Defects or Zero Stuck-At-Faults – CMOS IC Process Improvement, with IDDQ," IEEE, 1990 International Test Conference, pp. 255-256 (1990) <i>(No Month)</i>			✓
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RK	—	Steven McEuen, "WHY IDDQ?," IEEE, 1990 International Test Conference, p.252 (1990) <i>(No Month)</i>			✓
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RK	—	"Micromachine Technology," http://www.info.hqs.cae.ntt.jp/RD/ACT_act_3/micromachine.html , 2 pages (prior to May 16, 2001)			✓
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RK	—	LTX ValidMaster Plus Brochure (Prior to May 16, 2001) (USA)			—

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Sheet	5	of	5	Attorney Docket Number	53470P020D
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RK	—	"Fluorinert Liquid Heat Sink FC-3260," 3M New Product Announcement, January 1989			/
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RK	—	Howard W. Markstein, "Liquid Cooling Optimizes Heat Transfer," Electronic Packaging and Production, pp. 46-49 (April 1988)			/
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RK	—	J. Simon, S. Saffer, F. Sherman, and C.-J Kim, "Lateral Polysilicon Microrelays with a Mercury Micro-Drop Contact," pp. 1-15, 1998. <i>(No Month)</i>			—

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